



SCS Directory

Accreditation number: **SCS 0006**

International standard: ISO/IEC 17025:2017
Swiss standard: SN EN ISO/IEC 17025:2018

Kunz precision AG
Riedtalstrasse 16 A
4800 Zofingen

Head: Roland Zurbrügg
Responsible for MS: Roland Zurbrügg
Telephone: +41 62 746 00 20
E-Mail: <mailto:messdienst@kunz-precision.ch>
Internet: <http://www.kunz-precision.ch>
Initial accreditation: 10.07.1987
Current accreditation: 15.12.2018 to 14.12.2023
Scope of accreditation see: www.sas.admin.ch
(Accredited bodies)

Scope of accreditation as of 09.02.2022

Calibration laboratory for length and angles

Calibration and Measurement Capability (CMC)

| Measured Quantity / Instrument or Gauge | Measurement Range | Measurement Conditions | Best Measurement Capability \pm ¹⁾ | Remarks |
|--------------------------------------------------------------------------------|-------------------------------------|------------------------|--------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------------------------------------------------|
| LENGTH Machine tools | up to 40 m | | $0,5 \mu\text{m} + 3 \cdot 10^{-6} \cdot L$ | Positioning precision with laser interferometer On-site calibration |
| Length measuring instruments Horizontal instruments Height gauges | up to 3 m up to 1 m up to 3 m | | $0,2 \mu\text{m} + 2 \cdot 10^{-6} \cdot L$ $0,2 \mu\text{m} + 2 \cdot 10^{-6} \cdot L$ | Error of indication, with laser interferometer and gauge blocks With step gauge With laser interferometer <u>Also on-site calibration</u> |
| Electronic length indicator | up to 12 mm | | $0,3 \mu\text{m} + 2,5 \cdot 10^{-6} \cdot L$ | <u>Comparison with reference length indicator</u> |



SCS Directory

Accreditation number: SCS 0006

| Measured Quantity / Instrument or Gauge | Measurement Range | Measurement Conditions | Best Measurement Capability \pm ¹⁾ | Remarks |
|--------------------------------------------------------------------------------|---------------------------------------------------------------------------------------------------------------------------|------------------------|------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| | Glass scale up to 1000 mm | | $0,5 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$ | With graduation marks or circular structures |
| Guideways Straightness | $L \leq 3 \text{ m}$ $L \leq 30 \text{ m}$ $L \leq 3 \text{ m}$ $L \leq 30 \text{ m}$ $L \leq 15 \text{ m}$ | | $0,1 \mu\text{m} + 0,4 \cdot 10^{-6} \cdot L + 0,025 \cdot A$ $0,5 \mu\text{m} + 0,4 \cdot 10^{-6} \cdot L + 0,025 \cdot A$ $0,2 \mu\text{m} + (0,15 + B/2000) \cdot 10^{-6} \cdot L$ | on-site calibration With straightness interferometer L = measured length A = indicated value With angle interferometer or electronic levels B = base length in mm |
| Straightness standards Straight edges Straightness Parallelism | up to 3 m | | $0,15 \mu\text{m} + 0,15 \cdot 10^{-6} \cdot L + 0,02 \cdot A$ $0,2 \mu\text{m} + 0,25 \cdot 10^{-6} \cdot L + 0,02 \cdot A$ | STRAIGHT-line method L = measured length A = indicated value |
| Squareness standards Squareness | up to 1400 mm up to 1000 mm up to 500 mm | | $0,5 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L + 0,02 \cdot A$ $0,2 \mu\text{m} + 0,2 \cdot 10^{-6} \cdot L + 0,02 \cdot A$ $0,2 \mu\text{m} + 1,5 \cdot 10^{-6} \cdot L + 0,02 \cdot A$ | STRAIGHT-line method (specimen reclining) SQUARE-master method (specimen upright) With rotatory table and STRAIGHT-line L = length A = indicated value |
| Surface plates Flatness | Minimal size 0,2 m x 0,2 m | | $0,5 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$ | Electronic levels L = length Also on-site calibration |
| Flatness artefacts Flatness and parallelism | Surface > 1 cm ² | | $0,4 \mu\text{m} + 0,5 \cdot 10^{-6} \cdot L$ | TOPO-method |



SCS Directory

Accreditation number: SCS 0006

| Measured Quantity / Instrument or Gauge | Measurement Range | Measurement Conditions | Best Measurement Capability \pm ¹⁾ | Remarks |
|-----------------------------------------------------------------|-------------------------------------------------------------|------------------------|-----------------------------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| | up to 3000 mm | | | L= measured length |
| ANGLE Angular deviation of guideways | up to 100" | | 0,2" $+ 2 \cdot 10^{-3} \cdot A + 0,05" \cdot L$ | Angle interferometer A = value L = measured length in m Also on-site calibration |
| Dividing heads Rotary tables / Position error of rotary axes | Full circle 1° or arbitrary interval 10° interval | | 1,2" 0,5" | With rotary axis calibrator, or index table with angle interferometer or electronic level Optical polygon and autocollimator Also on-site calibration |
| Digital inclinometers | 360° 1° interval | | 2,5" | With index table |
| Angle encoders | 360° arbitrary interval | | 10" | With rotary table |
| Optical polygons | 360° arbitrary interval | | 0,3" | With rotary table and autocollimator |

* / * / * / * / *